

International Rectifier HEXFET® POWER MOSFET

Provisional Data Sheet No. PD 9.1285C

IRFY044CM

N-CHANNEL

60 Volt, 0.040Ω HEXFET

HEXFET technology is the key to International Rectifier's advanced line of power MOSFET transistors. The efficient geometry design achieves very low on-state resistance combined with high transconductance.

HEXFET transistors also feature all of the well-established advantages of MOSFETs, such as voltage control, very fast switching, ease of paralleling and electrical parameter temperature stability. They are well-suited for applications such as switching power supplies, motor controls, inverters, choppers, audio amplifiers, high energy pulse circuits, and virtually any application where high reliability is required.

The HEXFET transistor's totally isolated package eliminates the need for additional isolating material between the device and the heatsink. This improves thermal efficiency and reduces drain capacitance.

Product Summary

Part Number	BVDSS	RDS(on)	ID
IRFY044CM	60V	0.040Ω	16A*

Features

- Hermetically sealed
- Electrically isolated
- Simple Drive Requirements
- Ease of Paralleling
- Ceramic eyelets

Absolute Maximum Ratings

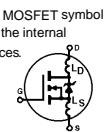
	Parameter	IRFY044CM	Units
ID @ VGS=10V, TC = 25°C	Continuous Drain Current	16*	A
ID @ VGS=10V, TC = 100°C	Continuous Drain Current	16*	
IDM	Pulsed Drain Current ①	156	
PD @ TC = 25°C	Max. Power Dissipation	100	W
	Linear Derating Factor	0.8	W/K⑤
VGS	Gate-to-Source Voltage	±20	V
EAS	Single Pulse Avalanche Energy ②	100	mJ
IAR	Avalanche Current ①	16*	A
EAR	Repetitive Avalanche Energy ①	10	mJ
dv/dt	Peak Diode Recovery dv/dt ③	4.5	V/ns
TJ	Operating Junction	-55 to 150	°C
Tstg	Storage Temperature Range		
	Lead Temperature	300 (0.063 in (1.6mm) from case for 10 sec)	
	Weight	4.3(typical)	g

* ID current limited by pin diameter

IRFY044CM Device

Electrical Characteristics @ $T_j = 25^\circ\text{C}$ (Unless Otherwise Specified)

	Parameter	Min	Typ	Max	Units	Test Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	60	—	—	V	$\text{V}_{\text{GS}} = 0\text{V}, \text{I}_D = 1.0\text{mA}$
$\Delta \text{BV}_{\text{DSS}}/\Delta T_j$	Temperature Coefficient of Breakdown Voltage	—	0.68	—	V°C	Reference to 25°C , $\text{I}_D = 1.0\text{mA}$
$\text{R}_{\text{DS(on)}}$	Static Drain-to-Source	—	—	0.040	Ω	$\text{V}_{\text{GS}} = 10\text{V}, \text{I}_D = 16\text{A}$ ④
	On-State Resistance	—	—	—		
$\text{V}_{\text{GS(th)}}$	Gate Threshold Voltage	2.0	—	4.0	V	$\text{V}_{\text{DS}} = \text{V}_{\text{GS}}, \text{I}_D = 250\mu\text{A}$
g_{fs}	Forward Transconductance	17	—	—	$\text{S} (\text{m})$	$\text{V}_{\text{DS}} \geq 15\text{V}, \text{I}_{\text{DS}} = 16\text{A}$ ④
I_{DSS}	Zero Gate Voltage Drain Current	—	—	25	μA	$\text{V}_{\text{DS}} = 0.8 \times \text{max. rating}, \text{V}_{\text{GS}} = 0\text{V}$
		—	—	250		$\text{V}_{\text{DS}} = 0.8 \times \text{max. rating}$ $\text{V}_{\text{GS}} = 0\text{V}, T_j = 125^\circ\text{C}$
I_{GSS}	Gate-to-Source Leakage Forward	—	—	100	nA	$\text{V}_{\text{GS}} = 20\text{V}$
I_{GSS}	Gate-to-Source Leakage Reverse	—	—	-100		$\text{V}_{\text{GS}} = -20\text{V}$
Q_g	Total Gate Charge	29	—	88	nC	$\text{V}_{\text{GS}} = 10\text{V}, \text{I}_D = 16\text{A}$
Q_{gs}	Gate-to-Source Charge	6.7	—	15		$\text{V}_{\text{DS}} = \text{Max. Rating} \times 0.5$
Q_{gd}	Gate-to-Drain ('Miller') Charge	18	—	52		see figures 6 and 13
$\text{t}_{\text{d(on)}}$	Turn-On Delay Time	—	—	23	ns	$\text{V}_{\text{DD}} = 30\text{V}, \text{I}_D = 16\text{A}, \text{R}_G = 9.1\Omega$ $\text{V}_{\text{GS}} = 10\text{V}$ see figure 10
t_{r}	Rise Time	—	—	130		
$\text{t}_{\text{d(off)}}$	Turn-Off Delay Time	—	—	81		
t_{f}	Fall Time	—	—	79		
L-D	Internal Drain Inductance	—	8.7	—	nH	Measured from the drain lead, 6mm (0.25 in.) from package to center of die.
L-S	Internal Source Inductance	—	8.7	—		
C _{iss}	Input Capacitance	—	2400	—	pF	$\text{V}_{\text{GS}} = 0\text{V}, \text{V}_{\text{DS}} = 25\text{V}$ $f = 1.0\text{MHz}$. see figure 5
C _{oss}	Output Capacitance	—	1100	—		
C _{rss}	Reverse Transfer Capacitance	—	230	—		



Source-Drain Diode Ratings and Characteristics

	Parameter	Min	Typ	Max	Units	Test Conditions
I _S	Continuous Source Current (Body Diode)	—	—	16	A	Modified MOSFET symbol showing the integral reverse p-n junction rectifier.
I _{SM}	Pulse Source Current (Body Diode) ①	—	—	156		
V _{SD}	Diode Forward Voltage	—	—	2.5	V	$T_j = 25^\circ\text{C}, I_S = 16\text{A}, V_{\text{GS}} = 0\text{V}$ ④
t _{rr}	Reverse Recovery Time	—	—	220	ns	$T_j = 25^\circ\text{C}, I_F = 16\text{A}, dI/dt \leq 100 \text{ A}/\mu\text{s}$
Q _{RR}	Reverse Recovery Charge	—	—	1.6	μC	$\text{V}_{\text{DD}} \leq 50\text{V}$ ④
t _{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible. Turn-on speed is substantially controlled by L _S + L _D .				



Thermal Resistance

Parameter	Min	Typ	Max	Units	Test Conditions
R _{thJC} Junction-to-Case	—	—	1.25	K/W ⑤	
R _{thJA} Junction-to-Ambient	—	—	80		Typical socket mount
R _{thCS} Case-to-Sink	—	0.21	—		Mounting surface flat, smooth

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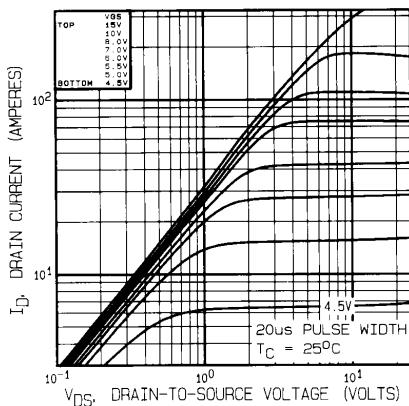


Fig. 1 — Typical Output Characteristics
 $T_c = 25^\circ\text{C}$

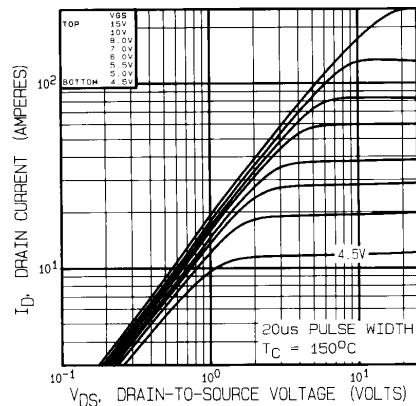


Fig. 2 — Typical Output Characteristics
 $T_c = 150^\circ\text{C}$

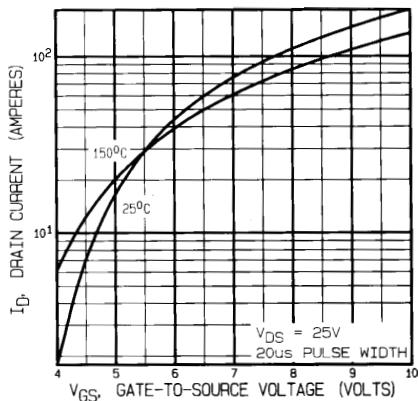


Fig. 3 — Typical Transfer Characteristics

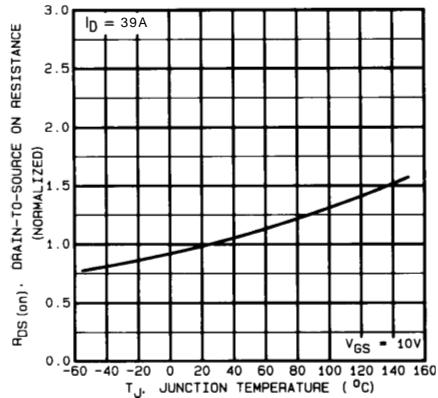


Fig. 4 — Normalized On-Resistance Vs. Temperature

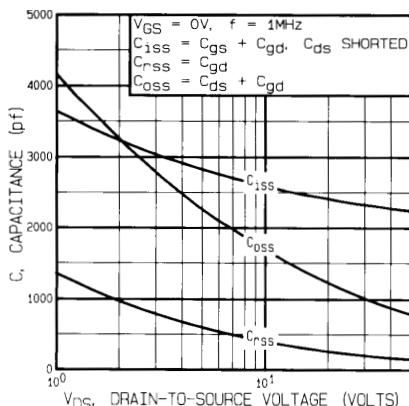


Fig. 5 — Typical Capacitance Vs. Drain-to-Source Voltage

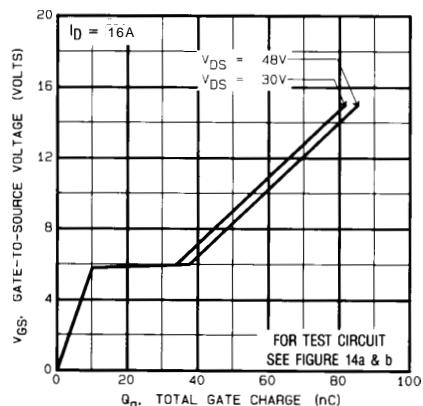


Fig. 6 — Typical Gate Charge Vs. Gate-to-Source Voltage

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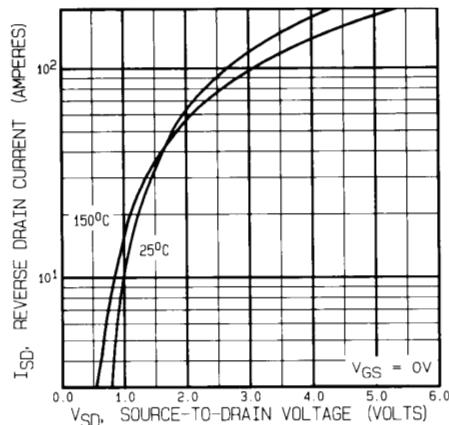


Fig. 7 — Typical Source-to-Drain Diode Forward Voltage

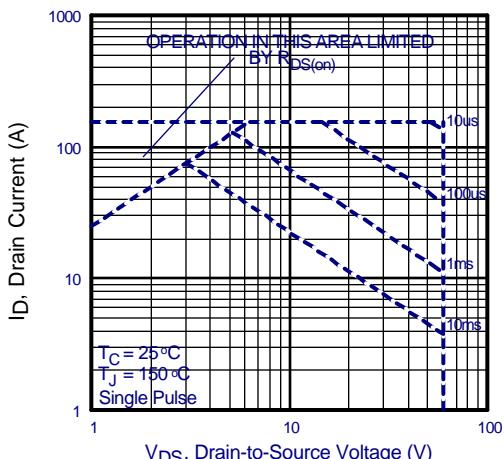


Fig. 8 — Maximum Safe Operating Area

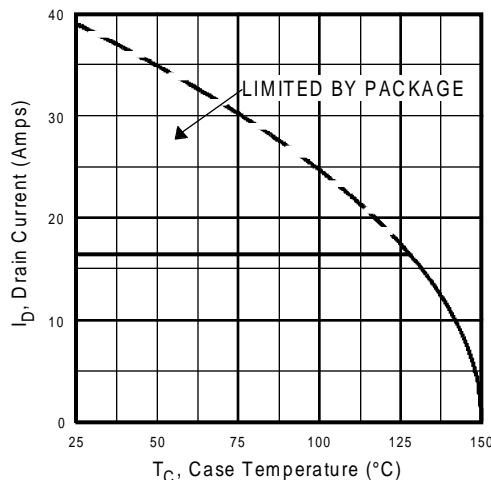


Fig. 9 — Maximum Drain Current Vs. Case Temperature

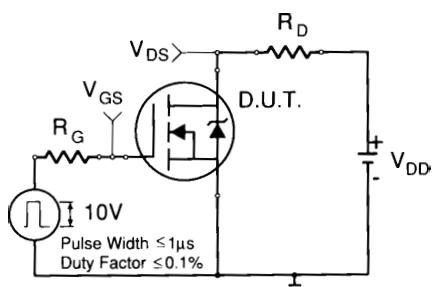


Fig. 10a — Switching Time Test Circuit

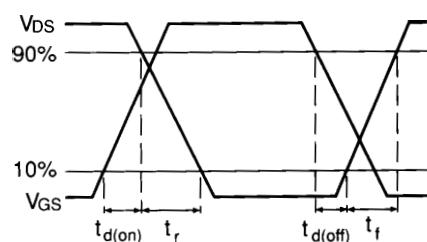


Fig. 10b — Switching Time Waveforms

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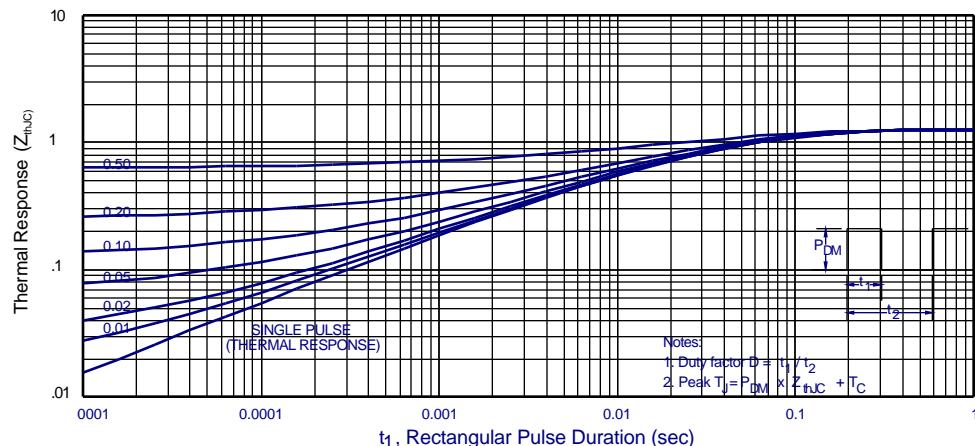


Fig. 11 — Maximum Effective Transient Thermal Impedance, Junction-to-Case Vs. Pulse Duration

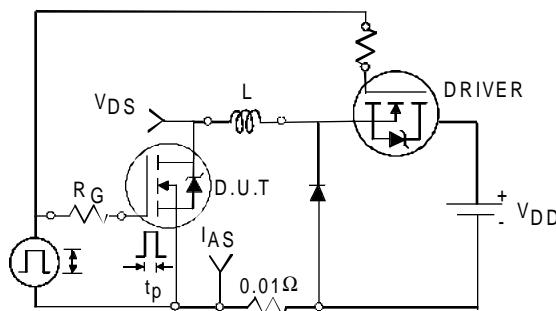


Fig. 12a — Unclamped Inductive Test Circuit

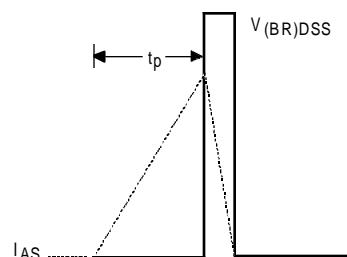


Fig. 12b — Unclamped Inductive Waveforms

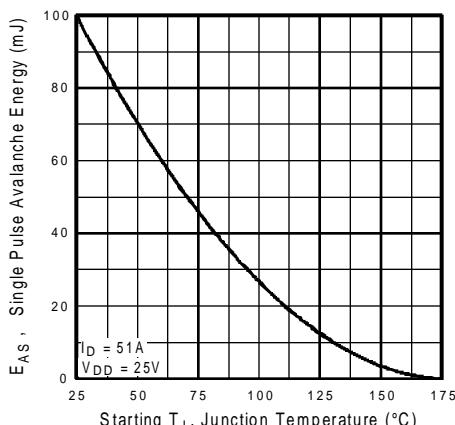


Fig. 12c — Max. Avalanche Energy vs. Current

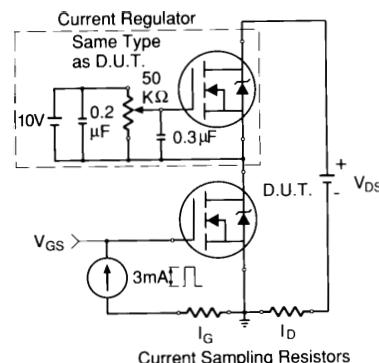


Fig. 13a — Gate Charge Test Circuit

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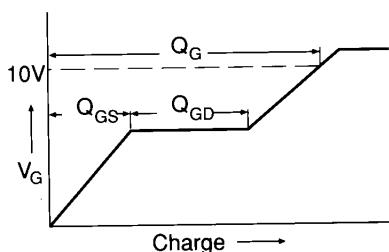
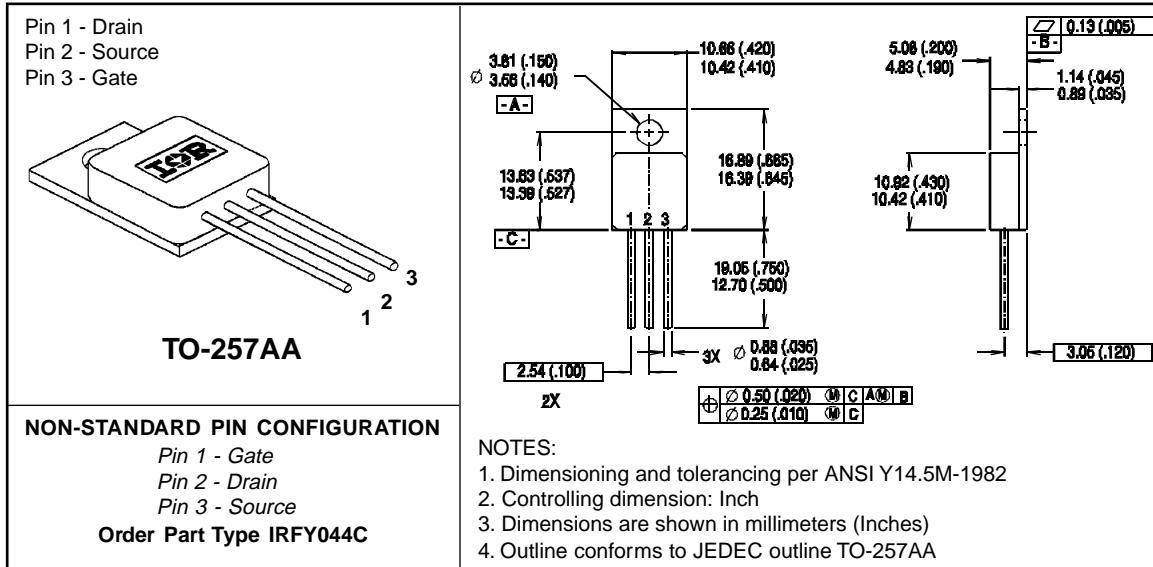


Fig. 13b — Basic Gate Charge Waveform

Case Outline and Dimensions



CAUTION

BERYLLIA WARNING PER MIL-PRF-19500

Packages containing beryllia shall not be ground, sandblasted, machined or have other operations performed on them which will produce beryllia or beryllium dust. Furthermore, beryllium oxide packages shall not be placed in acids that will produce fumes containing beryllium.

International
IR Rectifier

WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, Tel: (310) 322 3331

EUROPEAN HEADQUARTERS: Hurst Green, Oxted, Surrey RH8 9BB, UK Tel: ++ 44(0) 1883 732020

IR CANADA: 7321 Victoria Park Ave., Suite 201, Markham, Ontario L3R 2Z8, Tel: (905) 475 1897

IR GERMANY: Saalburgstrasse 157, 61350 Bad Homburg Tel: ++ 49 6172 96590

IR ITALY: Via Liguria 49, 10071 Borgaro, Torino Tel: ++ 39 11 451 0111

IR FAR EAST: K&H Bldg., 2F, 3-30-4 Nishi-Ikeburo 3-Chome, Toshima-Ki, Tokyo Japan 171 Tel: 81 3 3983 0086

IR SOUTHEAST ASIA: 315 Outram Road, #10-02 Tan Boon Liat Building, Singapore 0316 Tel: 65 221 8371